

# Search Notes



Application/Control No.

10/658,870

Examiner

Yon Couso

Applicant(s)/Patent under Reexamination

ONEDA ET AL.

Art Unit

2624

## SEARCHED

Class	Subclass	Date	Examiner
382	232		
	233		
	100		
	325	1-6-08	Ym
	240		
348	14.13		
358	426.02		
	426.03		
	426.01		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
P67	Pat searched		
	Interference		
	search included		
		1-6-08	Ym

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East searched		
IEEE author searched	1-6-08	Ym
PATM inventor searched		